

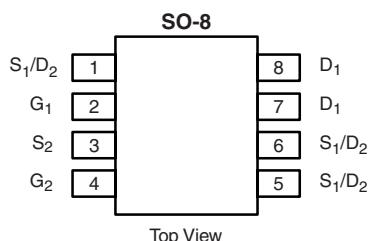
Dual N-Channel 30-V (D-S) MOSFET with Schottky Diode

PRODUCT SUMMARY

	V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^{a, e}	Q _g (Typ.)
Channel-1	30	0.0156 at V _{GS} = 10 V	8.0	7.3
		0.019 at V _{GS} = 4.5 V	8.0	
Channel-2	30	0.0156 at V _{GS} = 10 V	8.0	7.3
		0.019 at V _{GS} = 4.5 V	8.0	

SCHOTTKY PRODUCT SUMMARY

V_{DS} (V)	V_{SD} (V) Diode Forward Voltage	I_F (A) ^a
30	0.51 V at 1.0 A	2.0



FEATURES

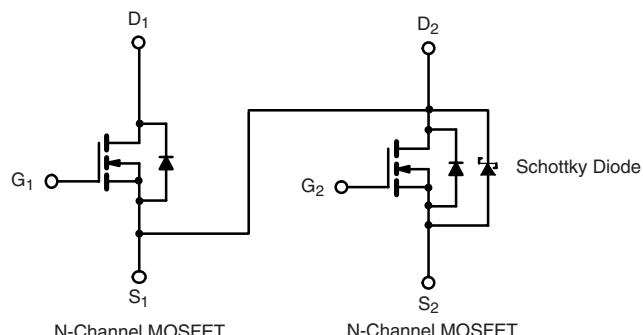
- Halogen-free According to IEC 61249-2-21
 - Definition
 - LITTLE FOOT® Plus Schottky
 - PWM Optimized
 - 100 % R_g Tested
 - 100 % UIS Tested
 - Compliant to RoHS Directive 2002/95/EC



**RoHS
COMPLIANT
HALOGEN
FREE**
Available

APPLICATIONS

- Notebook Logic dc-to-dc
 - Low Current dc-to-dc



ABSOLUTE MAXIMUM RATINGS $T_A = 25^\circ\text{C}$, unless otherwise noted

Parameter	Symbol	Channel-1	Channel-2	Unit
Drain-Source Voltage	V _{DS}	30	30	V
Gate-Source Voltage	V _{GS}	± 20	± 20	
Continuous Drain Current (T _J = 150 °C)	T _C = 25 °C	I _D	8.0 ^e	8.0 ^e
	T _C = 70 °C		7.1	7.1
	T _A = 25 °C		7.5 ^{b, c}	7.5 ^{b, c}
	T _A = 70 °C		5.8 ^{b, c}	5.8 ^{b, c}
Pulsed Drain Current (10 µs Pulse Width)	I _{DM}	30	30	A
Source-Drain Current Diode Current	T _C = 25 °C	I _S	2.6	
	T _A = 25 °C		1.8 ^{b, c}	
Pulsed Source-Drain Current	I _{SM}	30	30	
Single Pulse Avalanche Current	I _{AS}	10	10	mJ
Single Pulse Avalanche Energy	E _{AS}	5	5	
Maximum Power Dissipation	T _C = 25 °C	P _D	2.9	2.9
	T _C = 70 °C		1.8	1.8
	T _A = 25 °C		2 ^{b, c}	2 ^{b, c}
	T _A = 70 °C		1.2 ^{b, c}	1.2 ^{b, c}
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to 150		°C

THERMAL RESISTANCE RATINGS

Parameter		Symbol	Channel-1		Channel-2		Unit
			Typ.	Max.	Typ.	Max.	
Maximum Junction-to-Ambient ^{b, d}	$t \leq 10\text{ s}$	R_{thJA}	52	62.5	52	62.5	°C/W
Maximum Junction-to-Foot (Drain)	Steady State	R_{thJF}	35	43	35	43	

Notes:

- Notes:

 - a. Based on $T_C = 25^\circ\text{C}$.
 - b. Surface Mounted on 1" x 1" FR4 board.
 - c. $t = 10$ s.
 - d. Maximum under Steady State conditions is 110°C/W (Channel-1) and 110°C/W (Channel-2).
 - e. Package limited.

SPECIFICATIONS $T_J = 25^\circ\text{C}$, unless otherwise noted

Parameter	Symbol	Test Conditions	Min.	Typ. ^a	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	Ch-1	30		V	
		$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	Ch-2	30			
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	$I_D = 250 \mu\text{A}$	Ch-1	32		mV/ $^\circ\text{C}$	
$V_{GS(\text{th})}$ Temperature Coefficient	$\Delta V_{GS(\text{th})}/T_J$	$I_D = 250 \mu\text{A}$	Ch-1	- 6			
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 1 \text{ mA}$	Ch-1	1	3	V	
		$V_{DS} = V_{GS}, I_D = 1 \text{ mA}$	Ch-2	1	3		
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$	Ch-1		100	nA	
		$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$	Ch-2		100		
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$	Ch-1		0.001	mA	
		$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$	Ch-2		0.016		
		$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 100^\circ\text{C}$	Ch-1		0.025		
		$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 100^\circ\text{C}$	Ch-2	1.1	10		
On-State Drain Current ^b	$I_{D(on)}$	$V_{DS} = 5 \text{ V}, V_{GS} = 10 \text{ V}$	Ch-1	20		A	
		$V_{DS} = 5 \text{ V}, V_{GS} = 10 \text{ V}$	Ch-2	20			
Drain-Source On-State Resistance ^b	$R_{DS(on)}$	$V_{GS} = 10 \text{ V}, I_D = 8 \text{ A}$	Ch-1		0.0156	Ω	
		$V_{GS} = 10 \text{ V}, I_D = 8 \text{ A}$	Ch-2		0.0156		
		$V_{GS} = 4.5 \text{ V}, I_D = 5 \text{ A}$	Ch-1		0.019		
		$V_{GS} = 4.5 \text{ V}, I_D = 5 \text{ A}$	Ch-2		0.019		
Forward Transconductance ^b	g_{fs}	$V_{DS} = 15 \text{ V}, I_D = 8 \text{ A}$	Ch-1		29	S	
		$V_{DS} = 15 \text{ V}, I_D = 8 \text{ A}$	Ch-2		29		
Dynamic^a							
Input Capacitance	C_{iss}	Channel-1 $V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	Ch-1		950	pF	
			Ch-2		950		
Output Capacitance	C_{oss}		Ch-1		155		
			Ch-2		185		
Reverse Transfer Capacitance	C_{rss}	Channel-2 $V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	Ch-1		65	nC	
			Ch-2		65		
Total Gate Charge	Q_g	$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 8 \text{ A}$	Ch-1		16.5	nC	
		$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 8 \text{ A}$	Ch-2		16.5		
Gate-Source Charge	Q_{gs}	Channel-1 $V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 8 \text{ A}$	Ch-1		7.3	nC	
			Ch-2		7.3		
		Channel-2 $V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 8 \text{ A}$	Ch-1		2.7		
			Ch-2		2.7		
Gate-Drain Charge	Q_{gd}	$f = 1 \text{ MHz}$	Ch-1		2.1	Ω	
			Ch-2		2.1		
Gate Resistance	R_g	$f = 1 \text{ MHz}$	Ch-1	0.2	1.2	Ω	
			Ch-2	0.2	1.2		

Notes:

a. Guaranteed by design, not subject to production testing.

b. Pulse test; pulse width $\leq 300 \mu\text{s}$, duty cycle $\leq 2\%$.

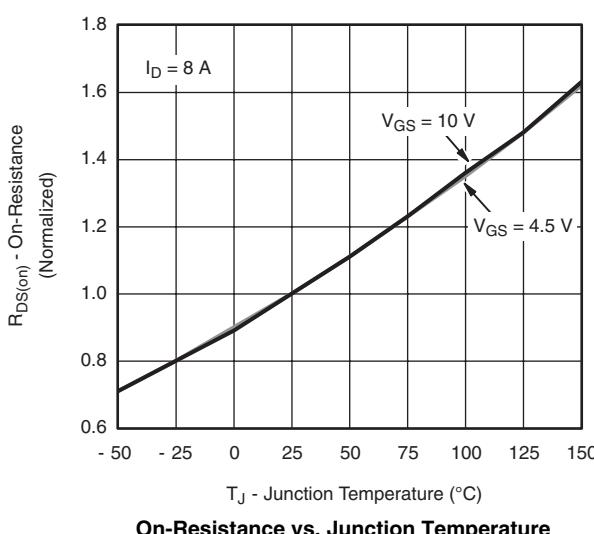
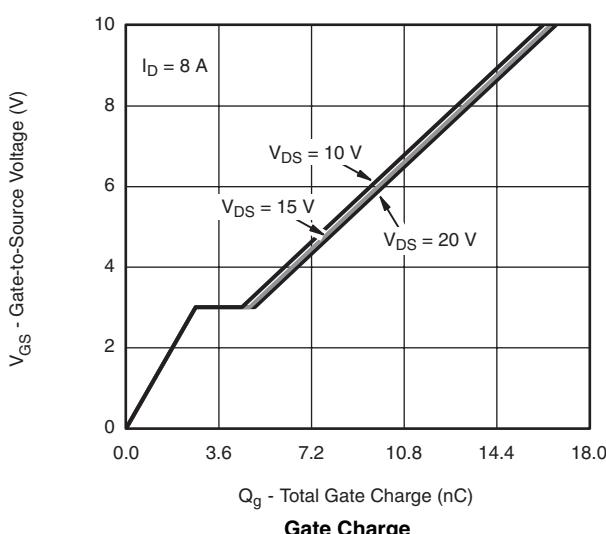
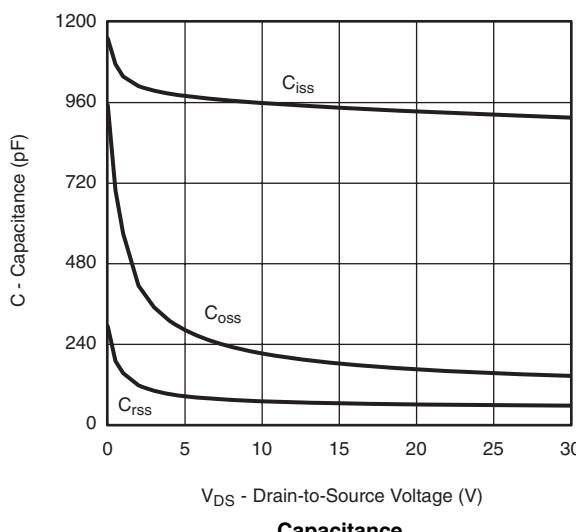
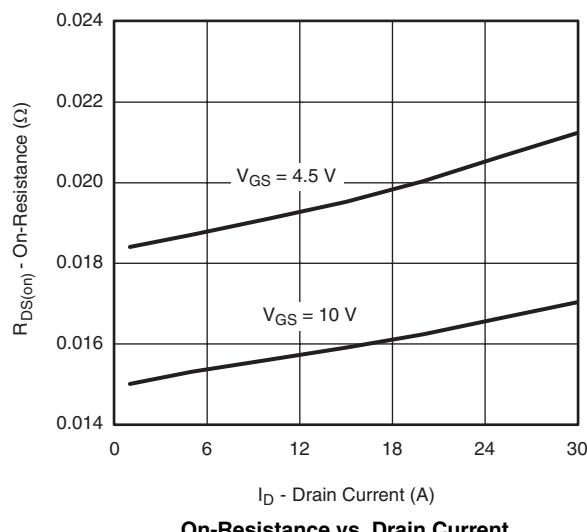
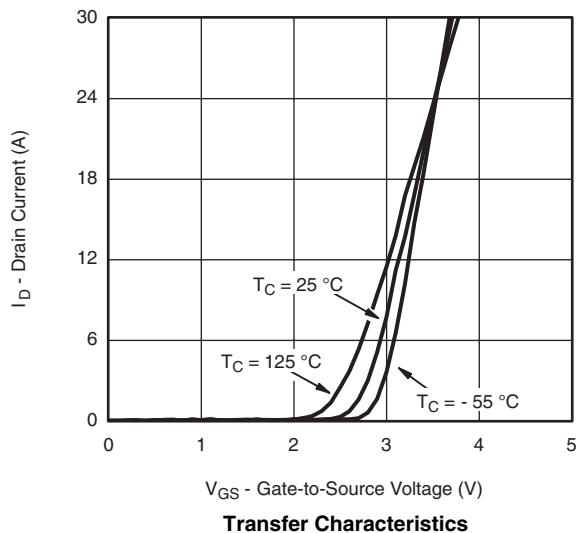
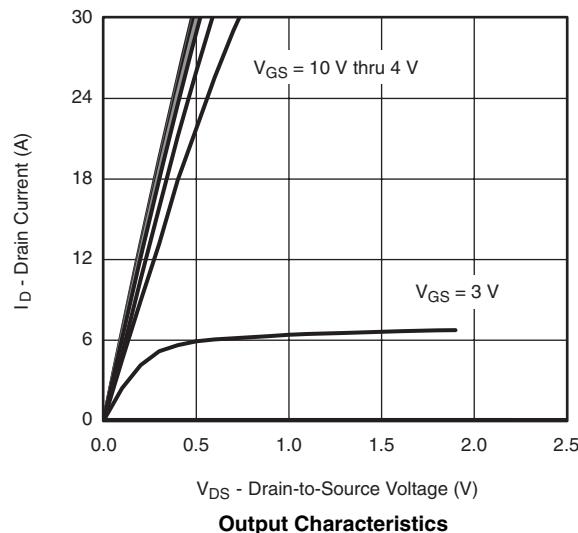
SPECIFICATIONS $T_J = 25^\circ\text{C}$, unless otherwise noted

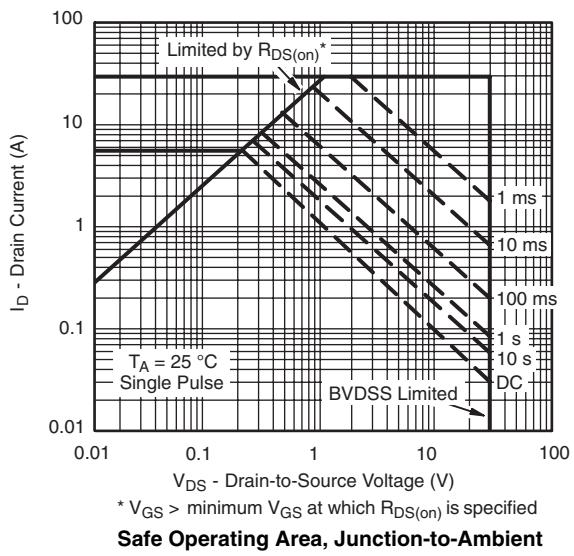
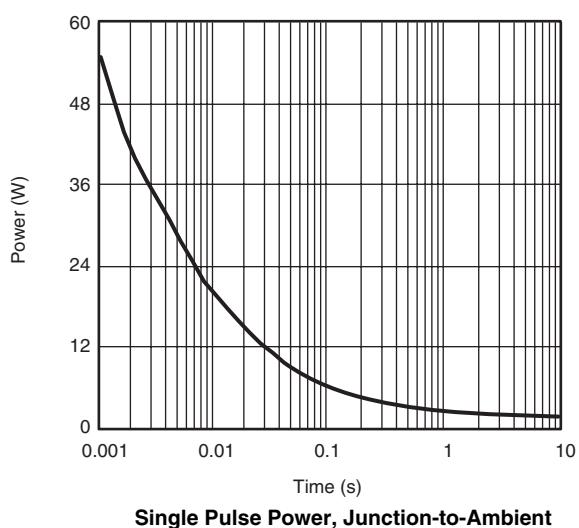
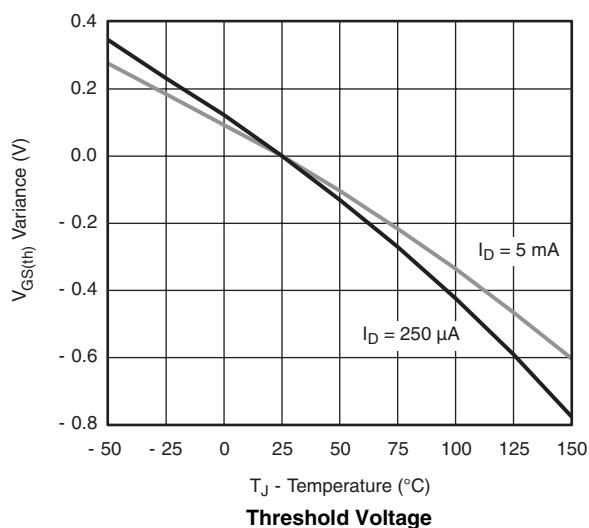
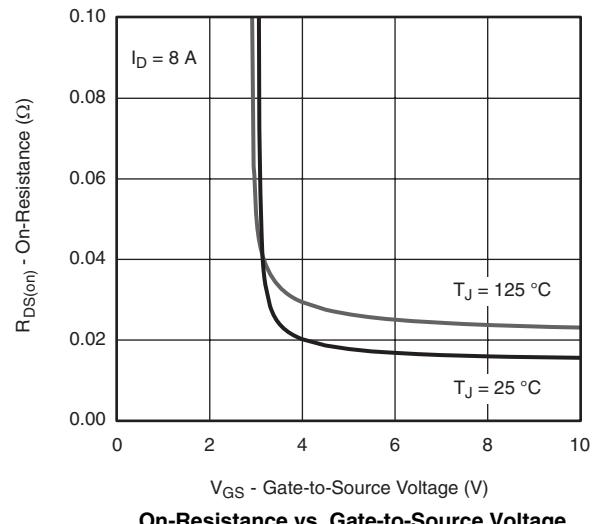
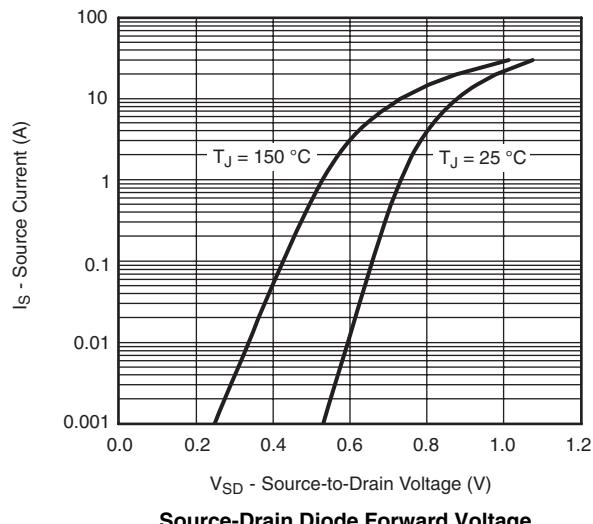
Parameter	Symbol	Test Conditions	Min.	Typ. ^a	Max.	Unit
Dynamic^a						
Turn-On Delay Time	$t_{d(on)}$	Channel-1 $V_{DD} = 15 \text{ V}, R_L = 3 \Omega$ $I_D \approx 5 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$	Ch-1	9	18	
			Ch-2	10	20	
Rise Time	t_r	Channel-2 $V_{DD} = 15 \text{ V}, R_L = 3 \Omega$ $I_D \approx 5 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$	Ch-1	11	20	
			Ch-2	10	20	
Turn-Off Delay Time	$t_{d(off)}$	Channel-1 $V_{DD} = 15 \text{ V}, R_L = 3 \Omega$ $I_D \approx 5 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$	Ch-1	18	35	
			Ch-2	18	35	
Fall Time	t_f	Channel-2 $V_{DD} = 15 \text{ V}, R_L = 3 \Omega$ $I_D \approx 5 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$	Ch-1	8	16	
			Ch-2	9	18	
Turn-On Delay Time	$t_{d(on)}$	Channel-1 $V_{DD} = 15 \text{ V}, R_L = 3 \Omega$ $I_D \approx 5 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$	Ch-1	17	35	
			Ch-2	17	35	
Rise Time	t_r	Channel-2 $V_{DD} = 15 \text{ V}, R_L = 3 \Omega$ $I_D \approx 5 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$	Ch-1	12	24	
			Ch-2	12	24	
Turn-Off Delay Time	$t_{d(off)}$	Channel-1 $V_{DD} = 15 \text{ V}, R_L = 3 \Omega$ $I_D \approx 5 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$	Ch-1	18	35	
			Ch-2	19	35	
Fall Time	t_f	Channel-2 $V_{DD} = 15 \text{ V}, R_L = 3 \Omega$ $I_D \approx 5 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$	Ch-1	10	20	
			Ch-2	10	20	
Drain-Source Body Diode Characteristics						
Continuous Source-Drain Diode Current	I_S	$T_C = 25^\circ\text{C}$	Ch-1		2.6	
			Ch-2		2.6	
Pulse Diode Forward Current ^a	I_{SM}		Ch-1		30	A
			Ch-2		30	
Body Diode Voltage	V_{SD}	$I_S = 1 \text{ A}$	Ch-1	0.74	1.1	V
			Ch-2	0.46	0.51	
Body Diode Reverse Recovery Time	t_{rr}	Channel-1 $I_F = 5 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}, T_J = 25^\circ\text{C}$	Ch-1	17	34	ns
			Ch-2	17	34	
Body Diode Reverse Recovery Charge	Q_{rr}	Channel-2 $I_F = 5 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}, T_J = 25^\circ\text{C}$	Ch-1	9	18	nC
			Ch-2	7	14	
Reverse Recovery Fall Time	t_a	Channel-1 $I_F = 5 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}, T_J = 25^\circ\text{C}$	Ch-1	10		
			Ch-2	9		
Reverse Recovery Rise Time	t_b	Channel-2 $I_F = 5 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}, T_J = 25^\circ\text{C}$	Ch-1	7		ns
			Ch-2	8		

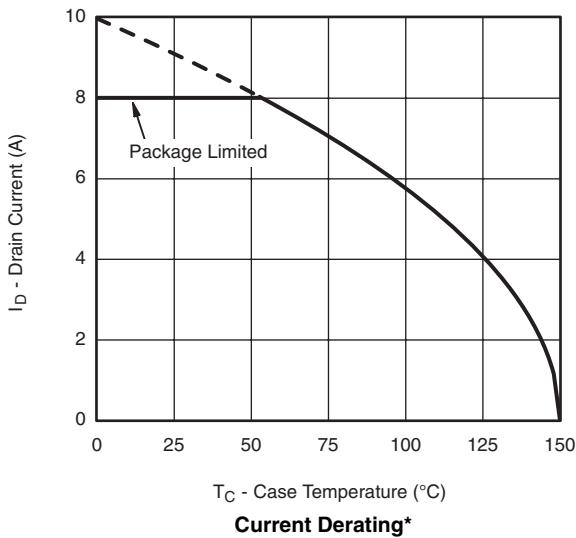
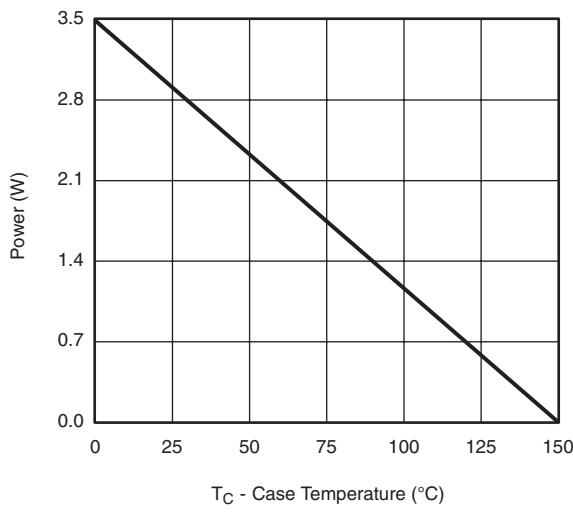
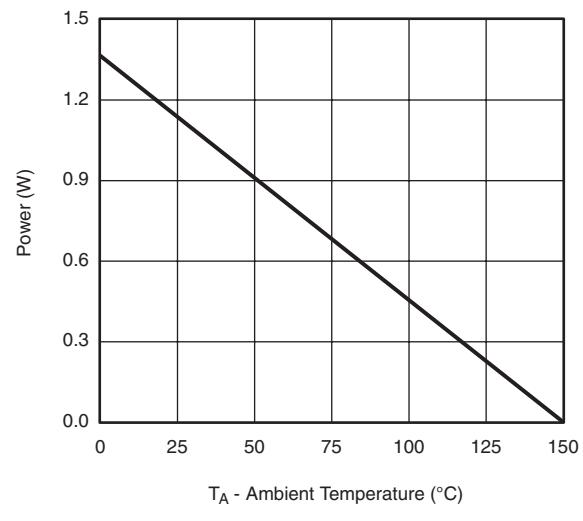
Notes:

- a. Guaranteed by design, not subject to production testing.
b. Pulse test; pulse width $\leq 300 \mu\text{s}$, duty cycle $\leq 2\%$.

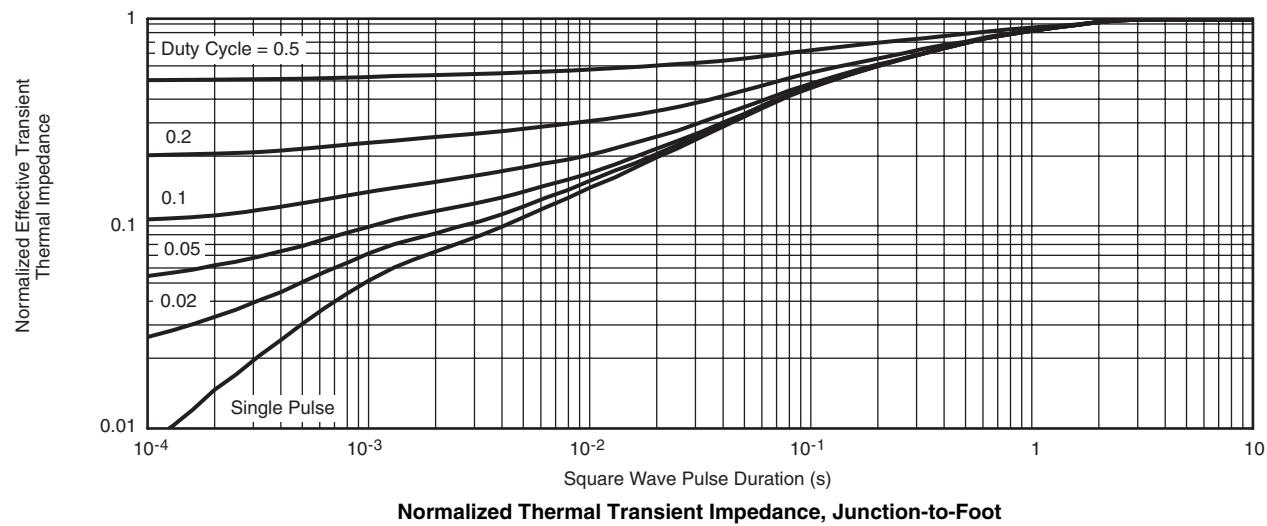
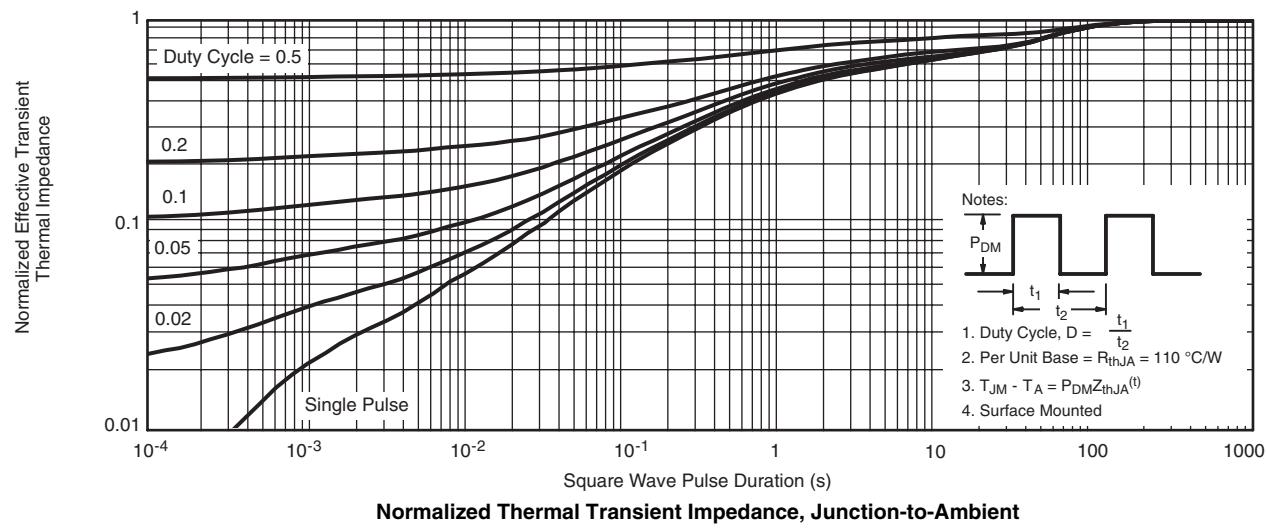
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

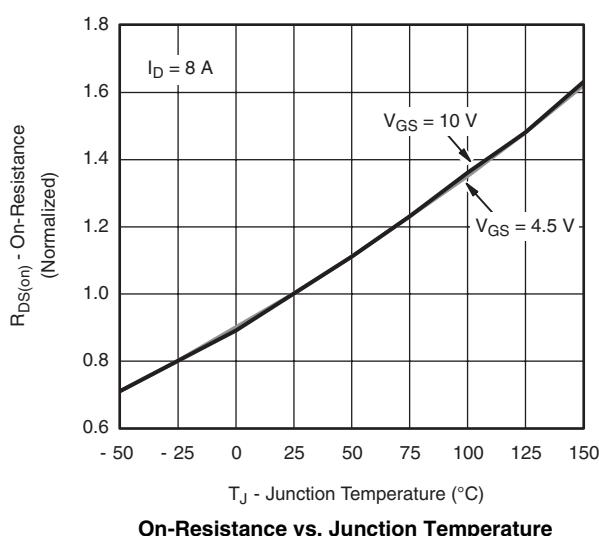
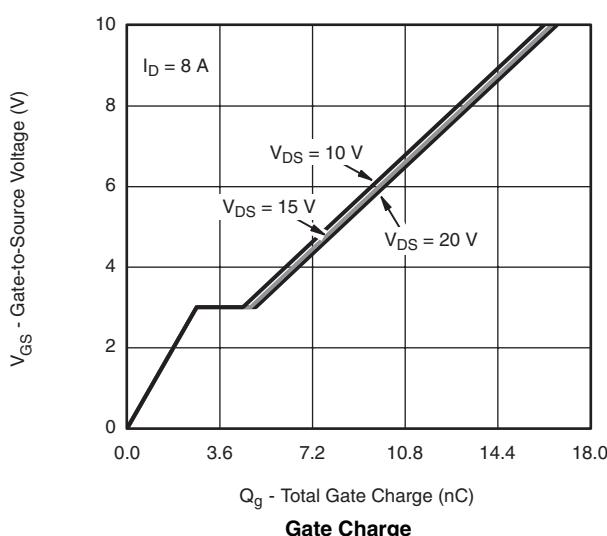
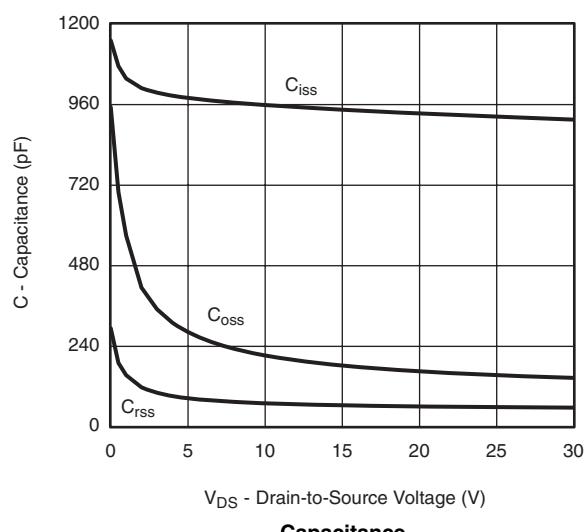
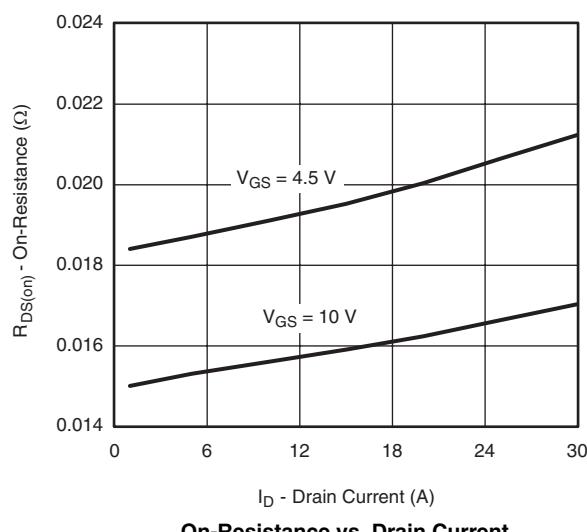
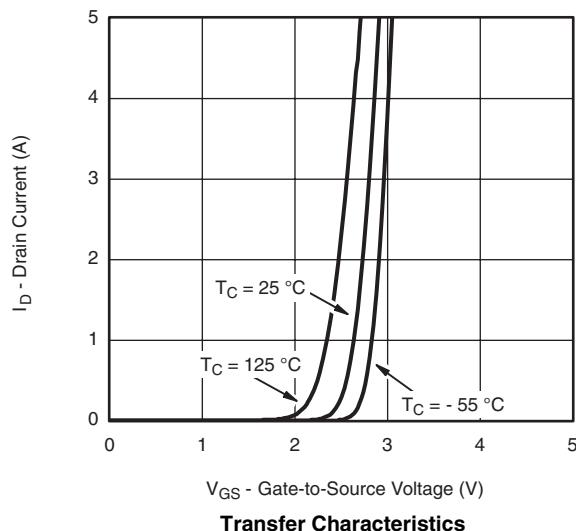
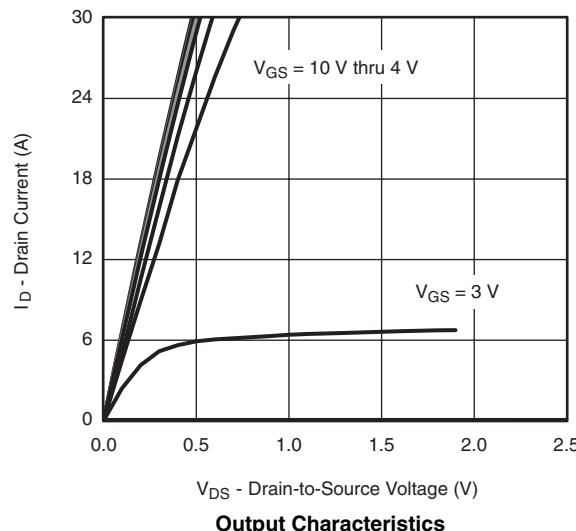
CHANNEL-1 TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted


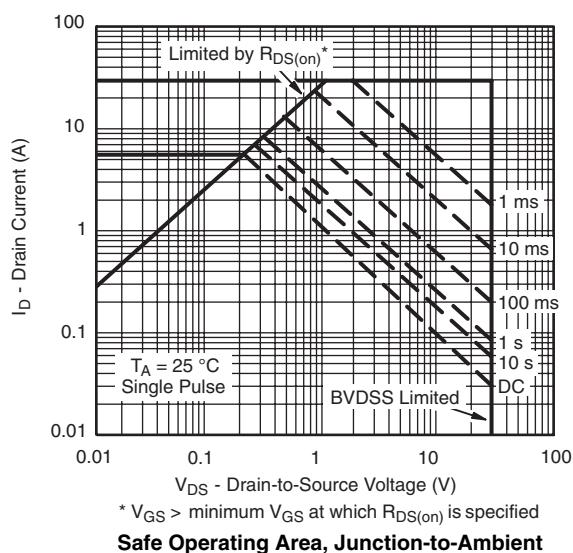
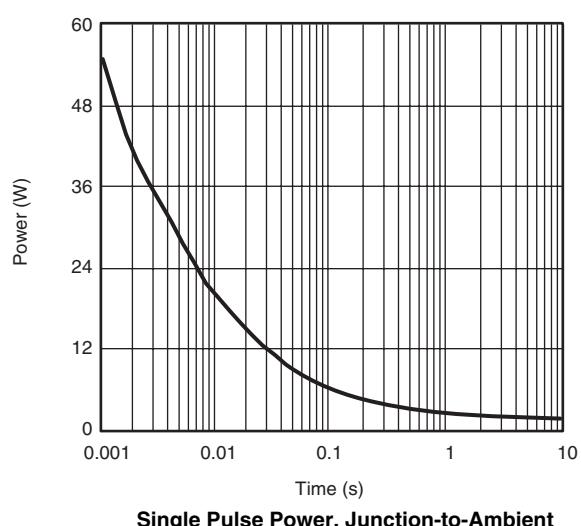
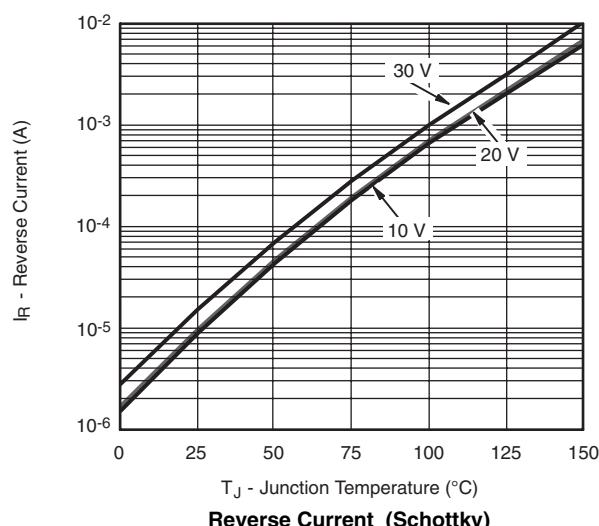
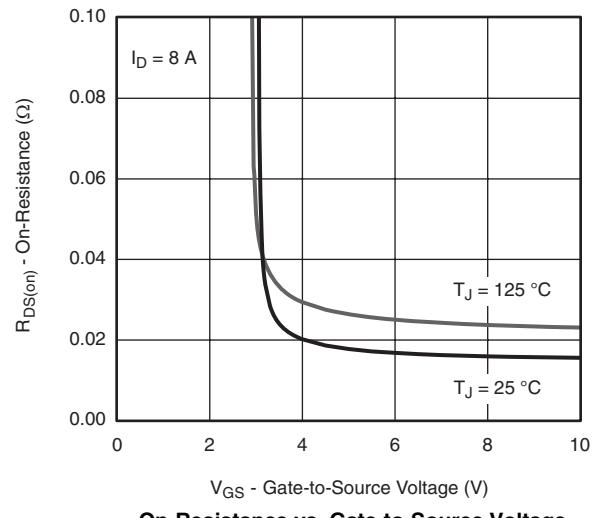
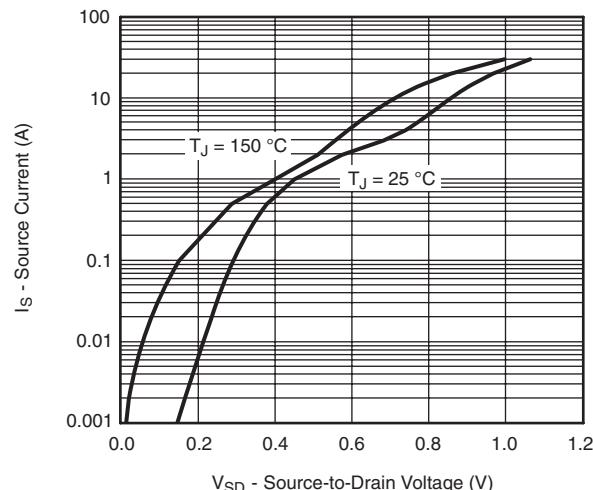
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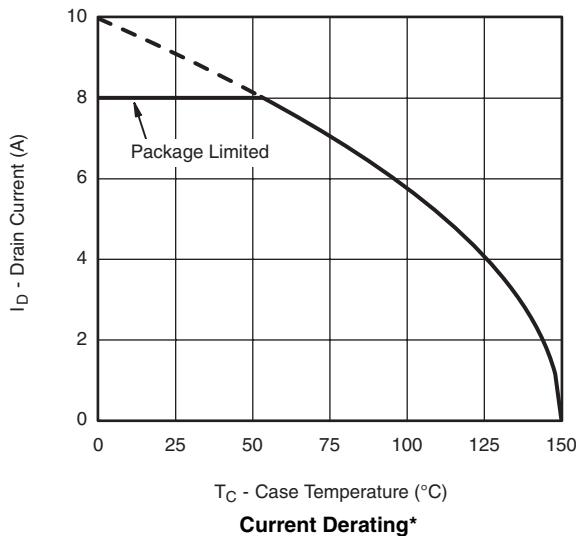
CHANNEL-1 TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted
**Current Derating***
Power Derating, Junction-to-Foot

Power Derating, Junction-to-Ambient

* The power dissipation P_D is based on $T_{J(\max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

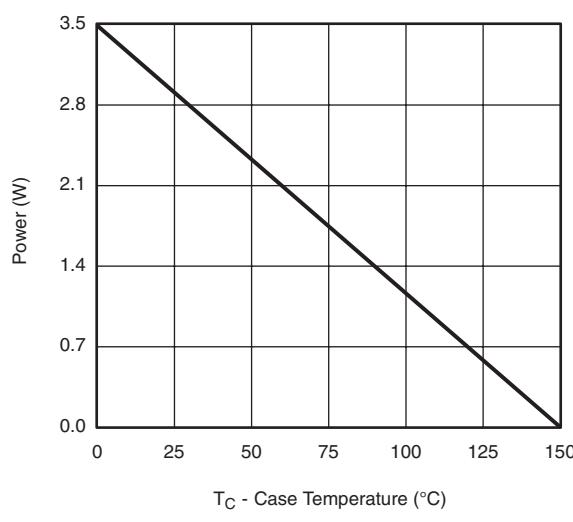
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CHANNEL-2 TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted


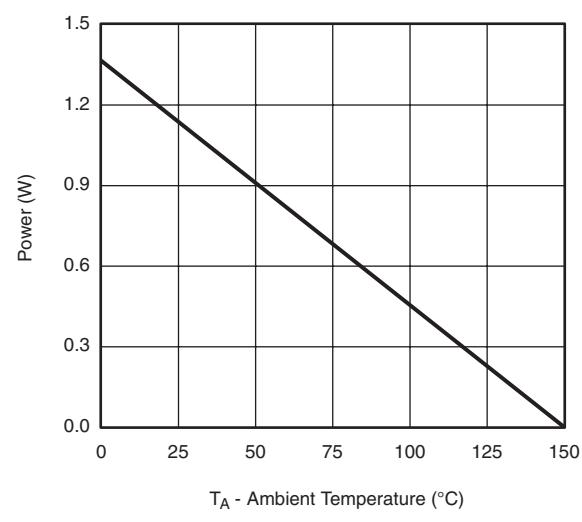
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CHANNEL-2 TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted


Current Derating*

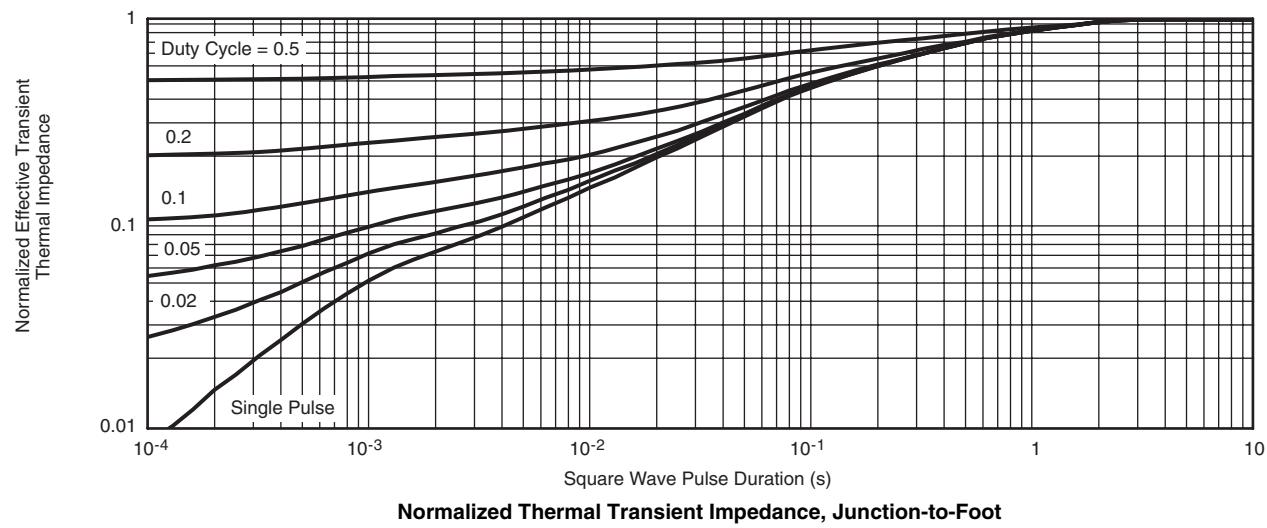
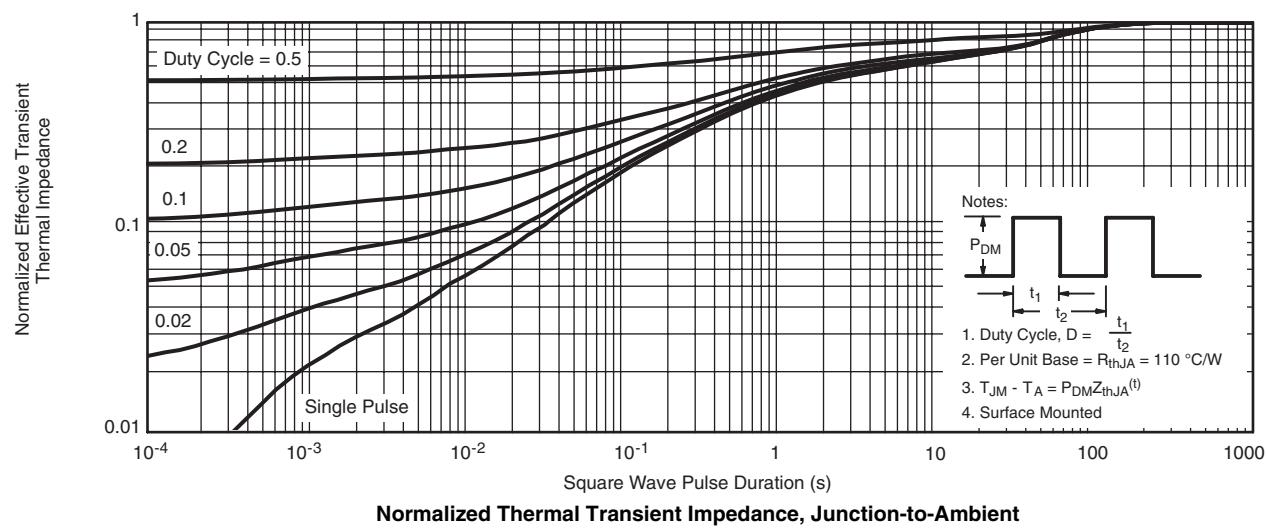


Power Derating, Junction-to-Foot



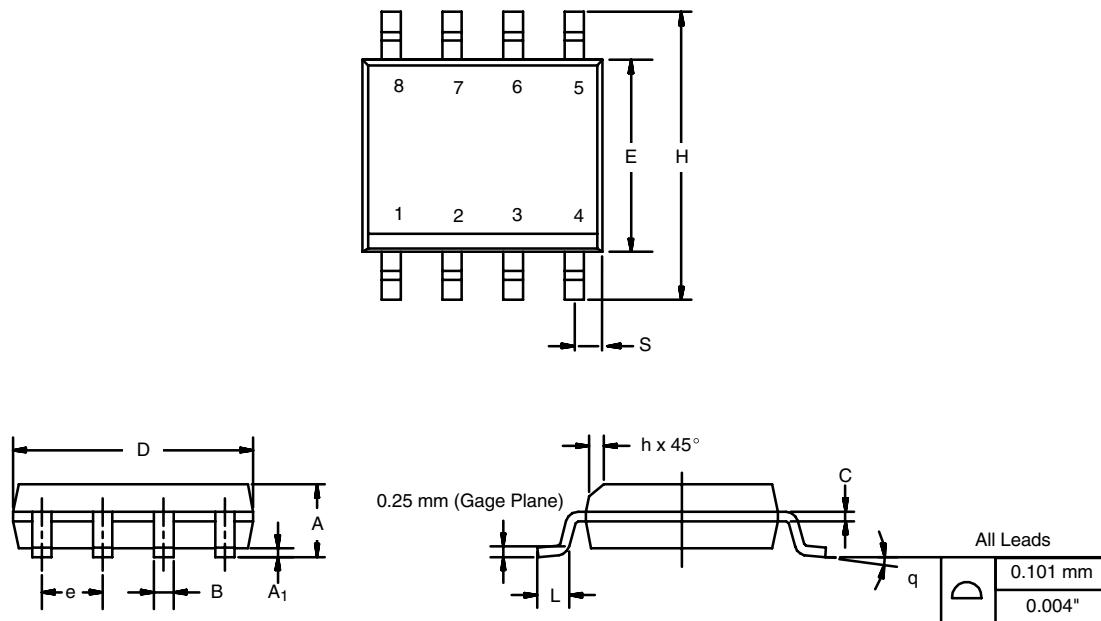
Power Derating, Junction-to-Ambient

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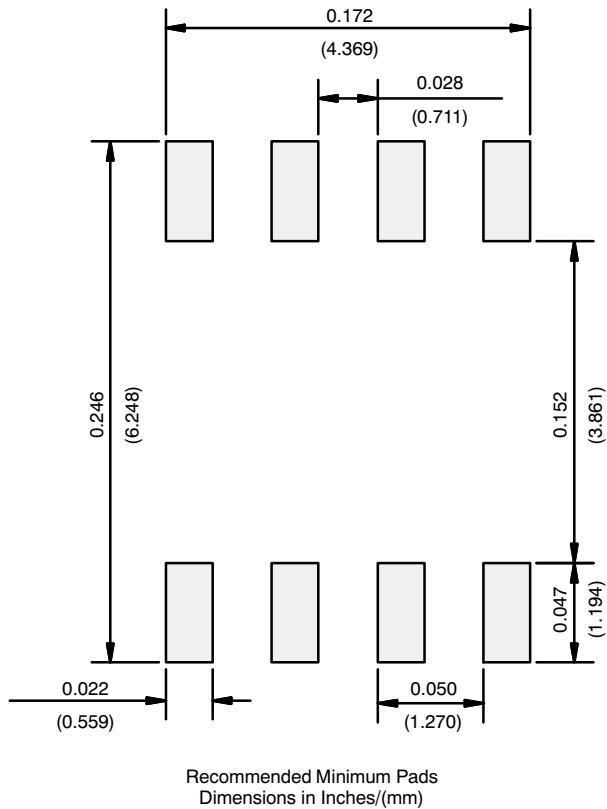
CHANNEL-2 TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted


SOIC (NARROW): 8-LEAD

JEDEC Part Number: MS-012



DIM	MILLIMETERS		INCHES	
	Min	Max	Min	Max
A	1.35	1.75	0.053	0.069
A ₁	0.10	0.20	0.004	0.008
B	0.35	0.51	0.014	0.020
C	0.19	0.25	0.0075	0.010
D	4.80	5.00	0.189	0.196
E	3.80	4.00	0.150	0.157
e	1.27 BSC		0.050 BSC	
H	5.80	6.20	0.228	0.244
h	0.25	0.50	0.010	0.020
L	0.50	0.93	0.020	0.037
q	0°	8°	0°	8°
S	0.44	0.64	0.018	0.026
ECN: C-06527-Rev. I, 11-Sep-06				
DWG: 5498				

RECOMMENDED MINIMUM PADS FOR SO-8

Disclaimer

All products due to improve reliability, function or design or for other reasons, product specifications and data are subject to change without notice.

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